

<b>Notice of References Cited</b>	Application/Control No. 10/573,471	Applicant(s)/Patent Under Reexamination TAKENAKA ET AL.	
	Examiner MCDIEUNEL MARC	Art Unit 3664	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0106495 A1	05-2006	Takenaka et al.	700/253
*	B	US-7,119,510 B2	10-2006	Kawai, Masakazu	318/568.12
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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